

# X-band HBT High Power Amplifier

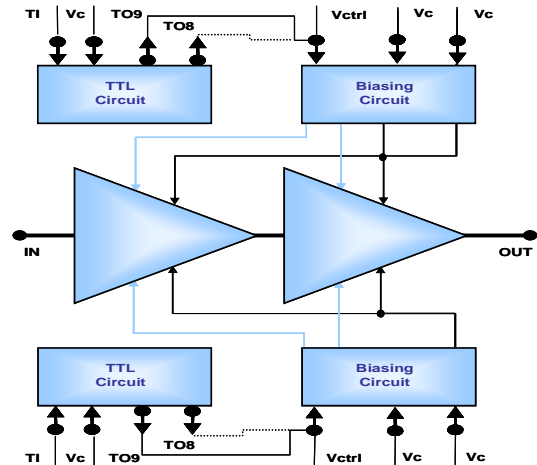
## GaAs Monolithic Microwave IC

### Description

The CHA8100 chip is a monolithic two-stage high power amplifier designed for X band applications. The HPA provides typically 11W output power, 40% power added efficiency and a high robustness on mismatched output. Moreover it includes:

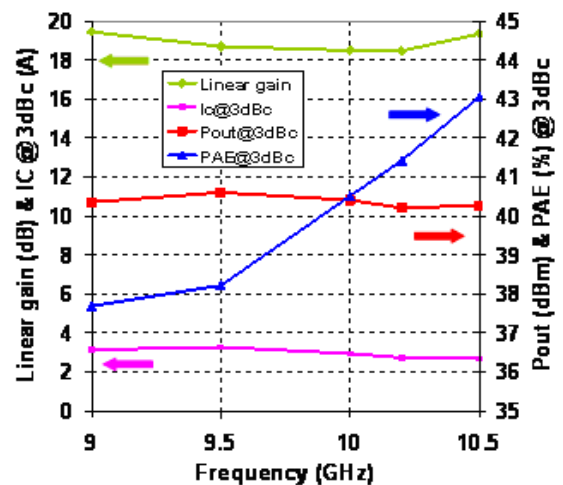
- an analogue biasing circuit that makes it less sensitive to spread and chip environment.
- an integrated TTL interface that enables to switch the HPA with a current consumption lower than 1mA

The circuit is 100% DC and RF tested on wafer to ensure performance compliance. This device is manufactured using a GaInP HBT process, including, via holes through the substrate and air bridges.



### Main Features

- 11W output power in pulse mode
- High gain: > 18dB @ 10GHz
- High PAE: 40% @ 10GHz
- Two biasing modes:
  - Digital control thanks to TTL interface
  - Analog control thanks to biasing circuit
- Chip size: 4.9 x 3.68 x 0.1mm<sup>3</sup>



### Main Characteristics

Vc=9V, Ic (Quiescent) = 2.1A, Pulse width=100μs, Duty cycle = 20%

Symbol	Parameter	Min	Typ	Max	Unit
Top	Operating temperature range (1)	-40		+80	°C
F_op	Operating frequency range	9		10.5	GHz
P_sat	Saturated output power @ 25°C		12.5		W
P_3dBc	Output power @ 3dBc @ 25°C		11		W
G_lin	Linear gain @ 25°C	17	18.5		dB

ESD Protections: Electrostatic discharge sensitive device. Observe handling precautions!  
(1) The reference is the back-side of the chip.

## Electrical Characteristics

Tamb = 25°C, Vc=9V, Ic (Quiescent) = 2.1A, Pulse width=100µs, Duty cycle = 20%

Symbol	Parameter	Min	Typ	Max	Unit
F_op	Operating frequency	9		10.5	GHz
G_lin	Linear gain (9 to 10GHz)	17	18.5		dB
G_lin_T	Linear gain variation versus temperature		-0.025		dB/°C
RL_in	Input Return Loss		-9		dB
RL_out	Output Return Loss		-15		dB
P_sat	Saturated output power		41		dBm
P_sat_T	Saturated output power variation versus temperature		-0.01		dB/°C
P_3dBc	Output power @ 3dBc (3)	39.5	40.5		dBm
PAE_3dBc	Power Added Efficiency @ 3dBc	35	40		%
Vc	Power supply voltage (3)	8		9	V
Ic	Power supply quiescent current (1)		2.1		A
TI	TTL input voltage	0		5	V
I_TI	TTL input current		0.7		mA
Vctrl	Collector current control voltage		5		V
Ictrl	Control supply current		22		mA
Zctr	Vctrl input port impedance (2)		350		Ohm
Top	Operating temperature range	-40		+85	°C

(1) Parameter tunable by Vctrl when control biasing circuit used.

(2) This value corresponds to the 4 ports in parallel

(3) 0.5V variation on Vc leads to around 0.4dB variation of the output power (impact on robustness see Maximum ratings)

## Absolute Maximum Ratings (1)

Tamb = 25°C

Symbol	Parameter	Values	Unit
Cmp	Compression level (2 & 3)	8	dB
Vc	Power supply voltage (4)	10	V
Ic	Power supply quiescent current	3	A
Ic_sat	Power supply current in saturation	4	A
Vctrl	Collector current control voltage	6.5	V
Tj	Maximum junction temperature (5)	175	°C
Tstg	Storage temperature range	-55 to +125	°C

(1) Operation of this device above any one of these parameters may cause permanent damage.

(2) For higher compression the level limit can be raised by decreasing the voltage Vc using the rate 0.5 V / dBc

(3) Vc=9V, Temperature=-40°C, Output VSWR=2:1

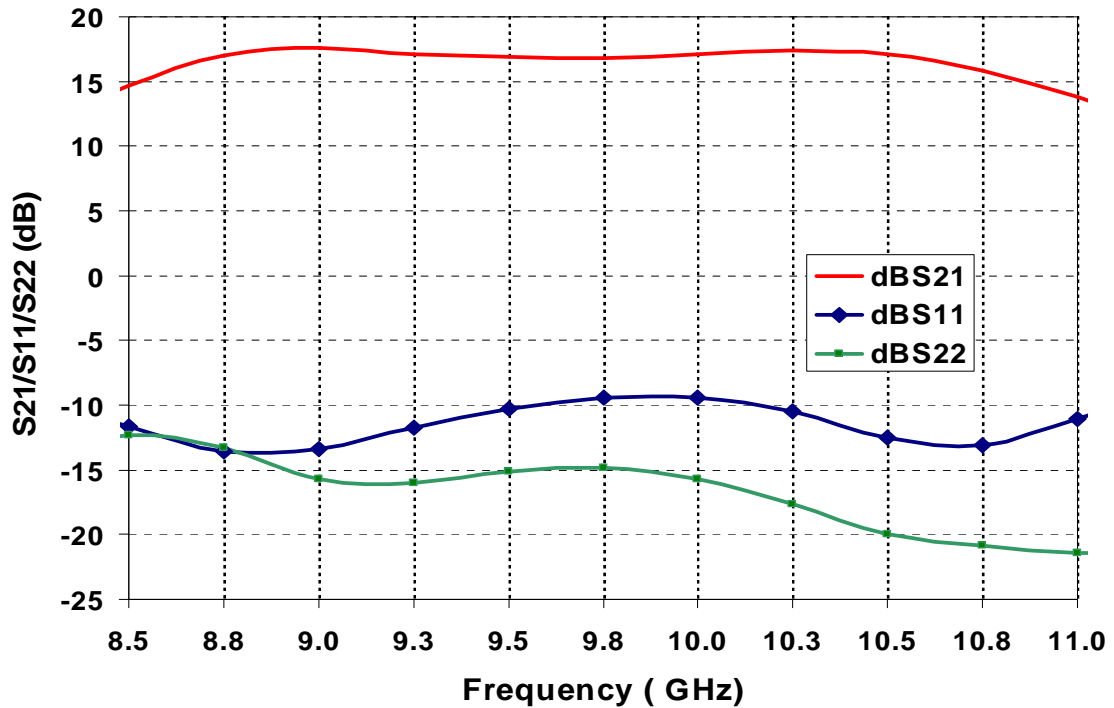
(4) Without RF input power

(5) Equivalent Thermal resistance to Backside: 6°C/W

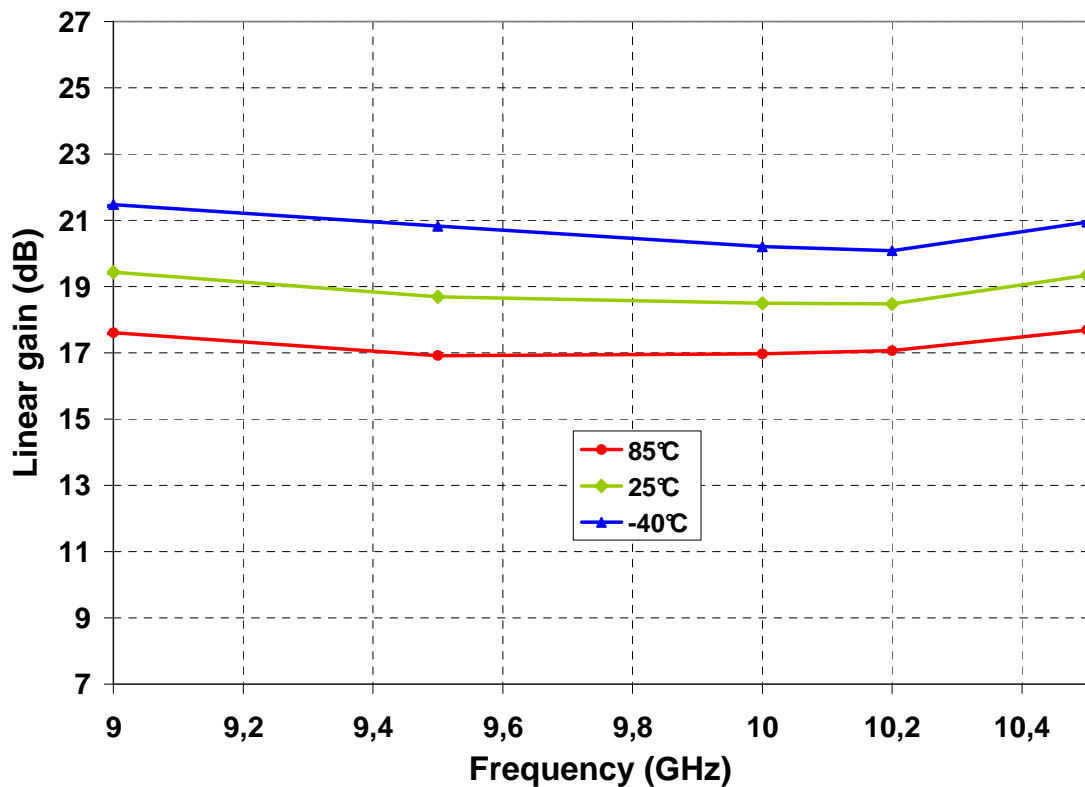
**Typical measured characteristics**

**Measurements on Jig:**

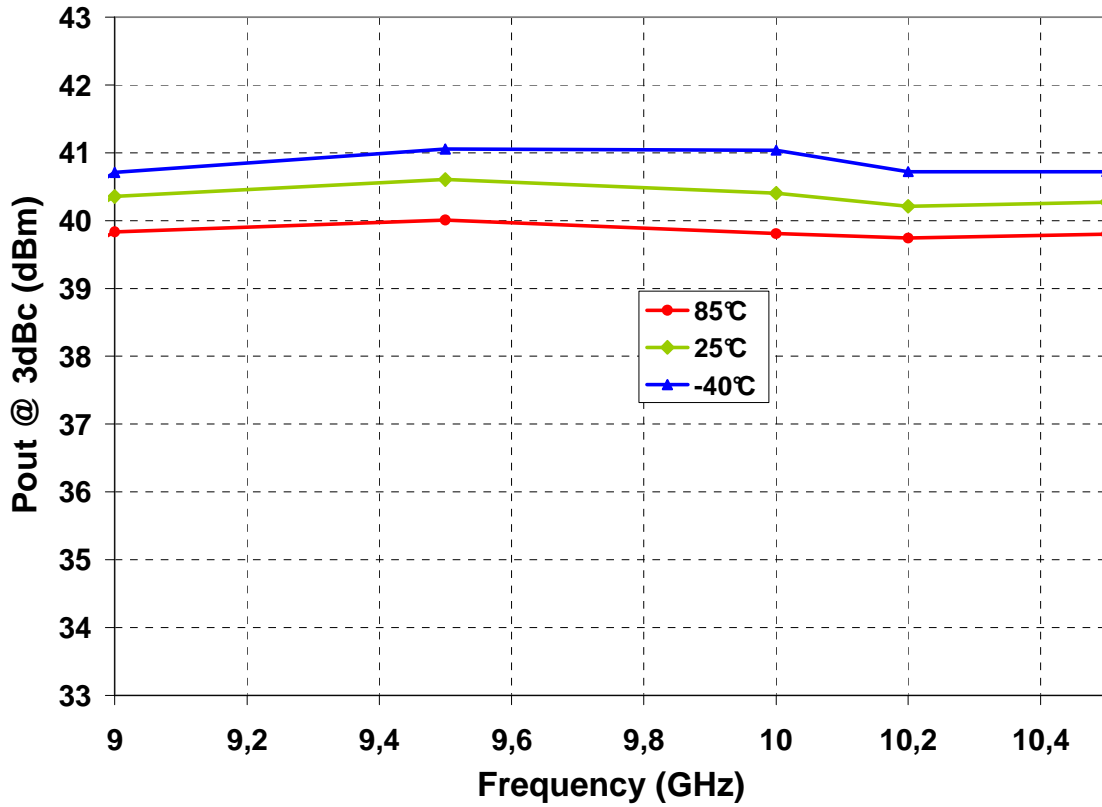
$V_c = 9V$ ,  $V_{TTL} = 5V$ ,  $I_c$  (Quiescent) = 2.1A, Pulse width=100 $\mu$ s, Duty cycle = 20%



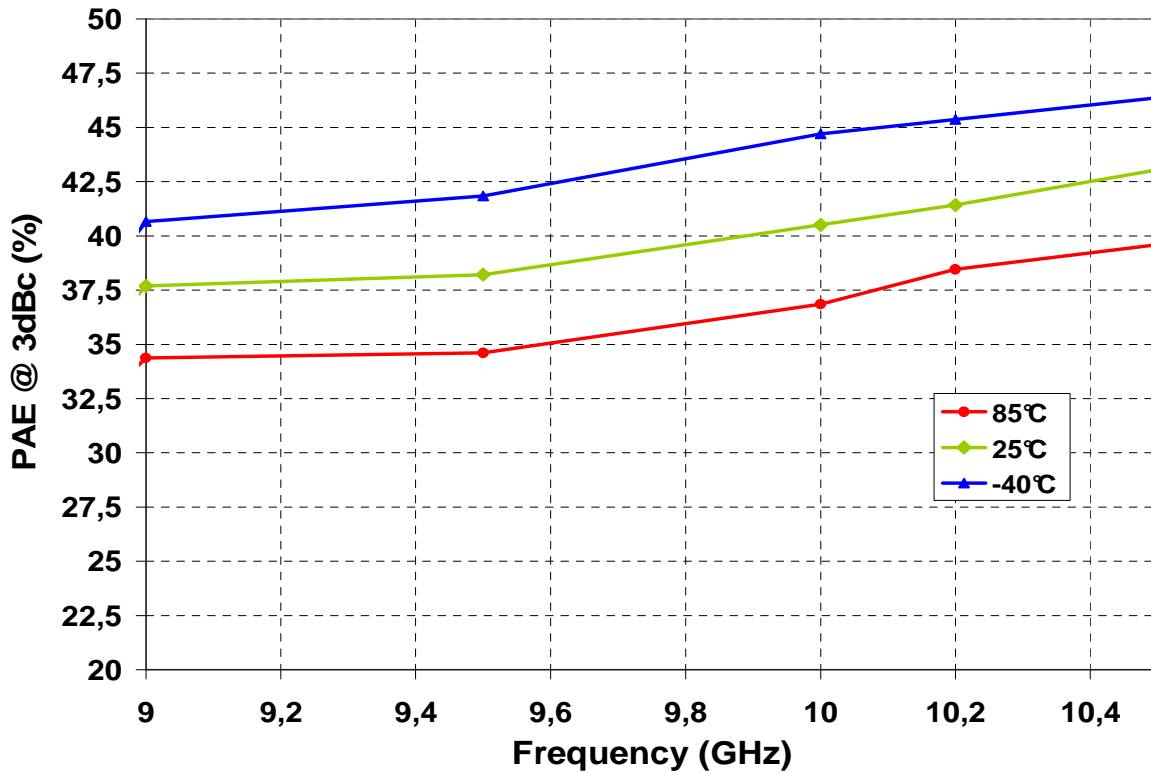
*Gain/Input & Output Return losses (dB). Temperature: +20°C*



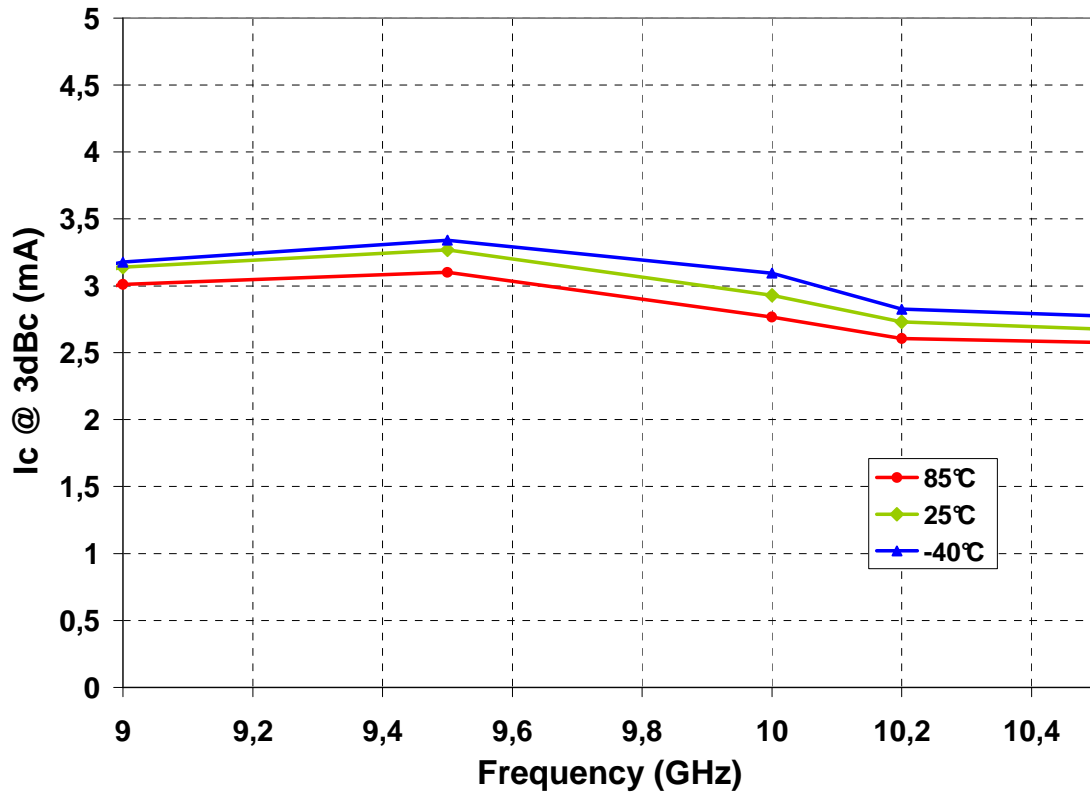
*Linear Gain versus frequency and temperature*



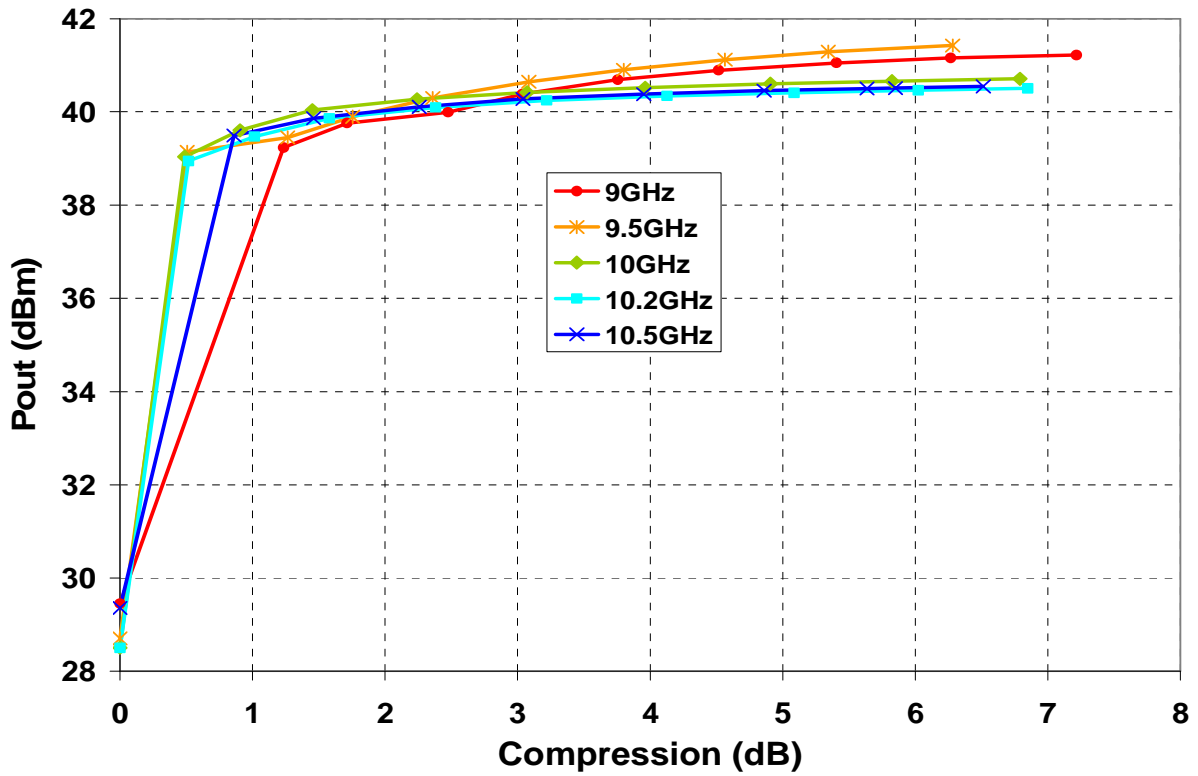
Output Power @ 3dBc versus frequency and temperature



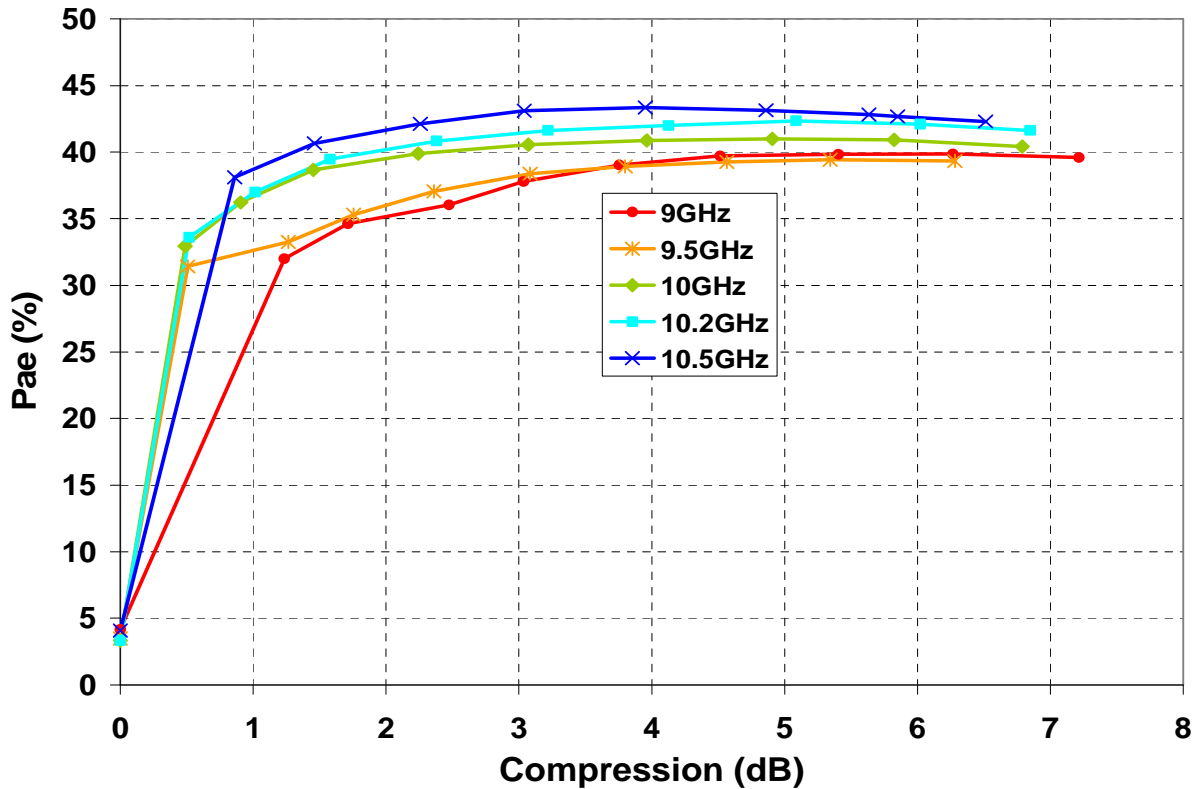
PAE @ 3dBc versus frequency and temperature



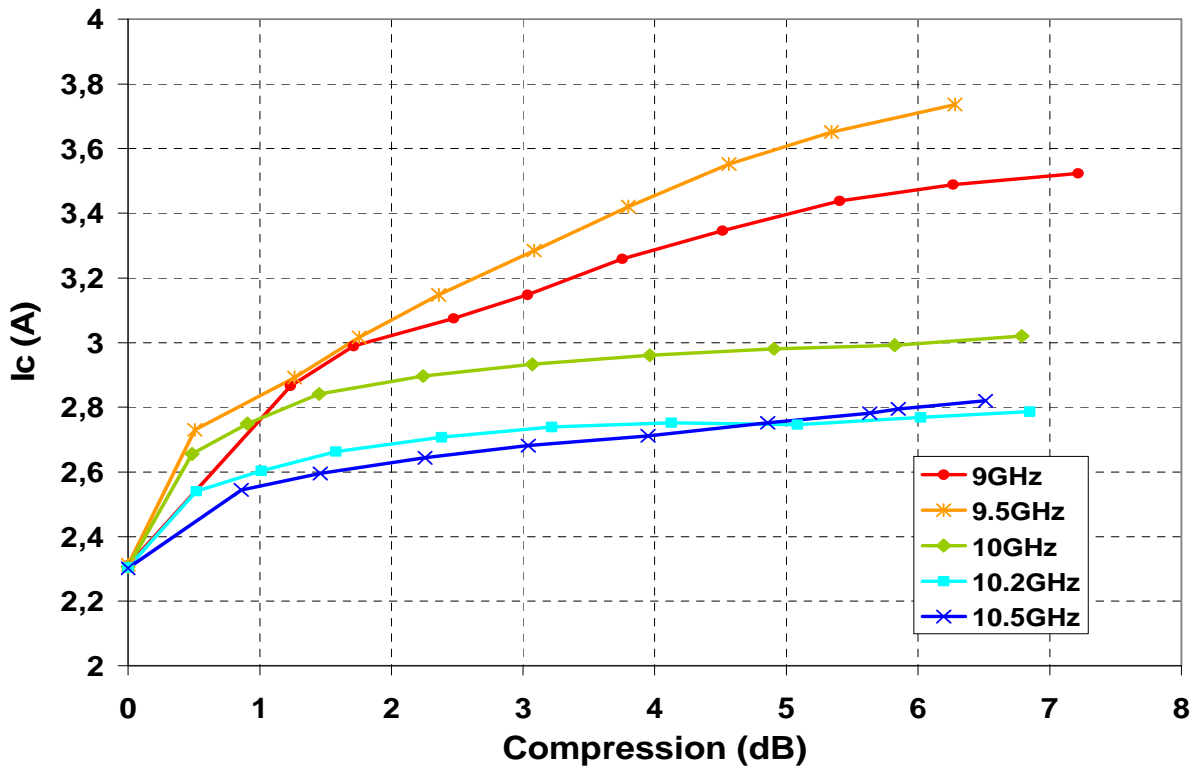
*Ic @ 3dBc versus frequency and temperature*



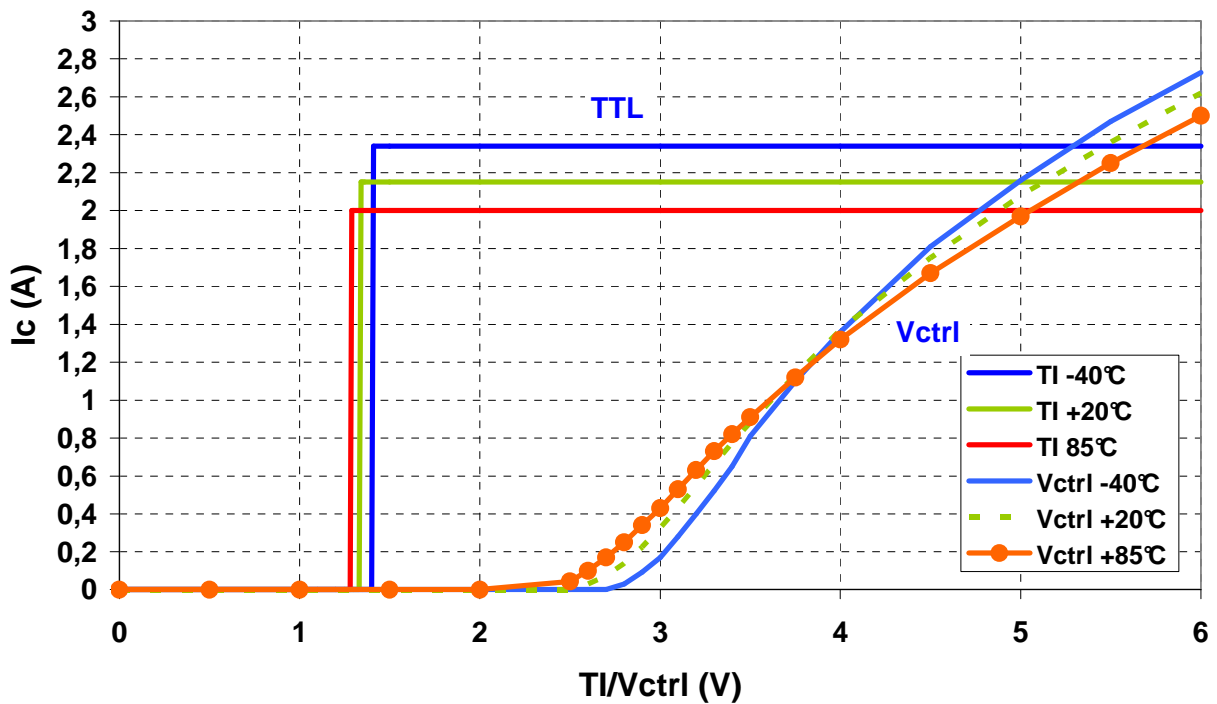
*Output Power @ 25°C versus compression and frequency*



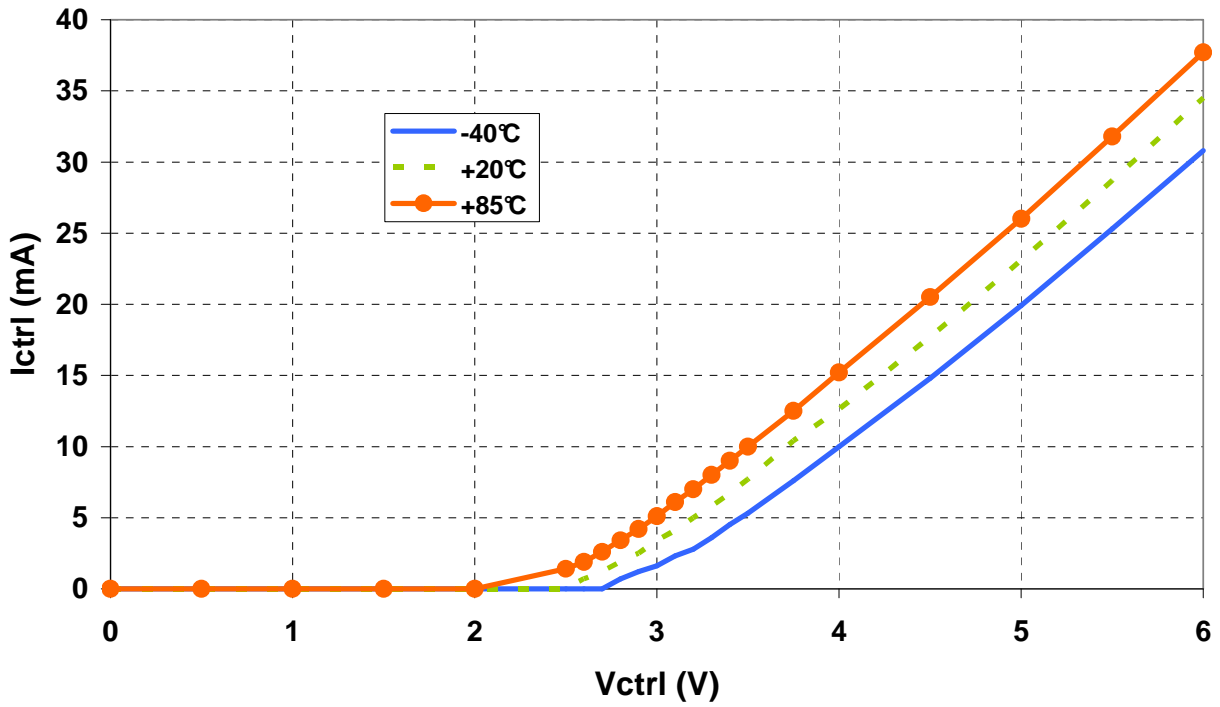
*PAE @ 25°C versus compression and frequency*



Collector current @ 25°C versus compression and frequency

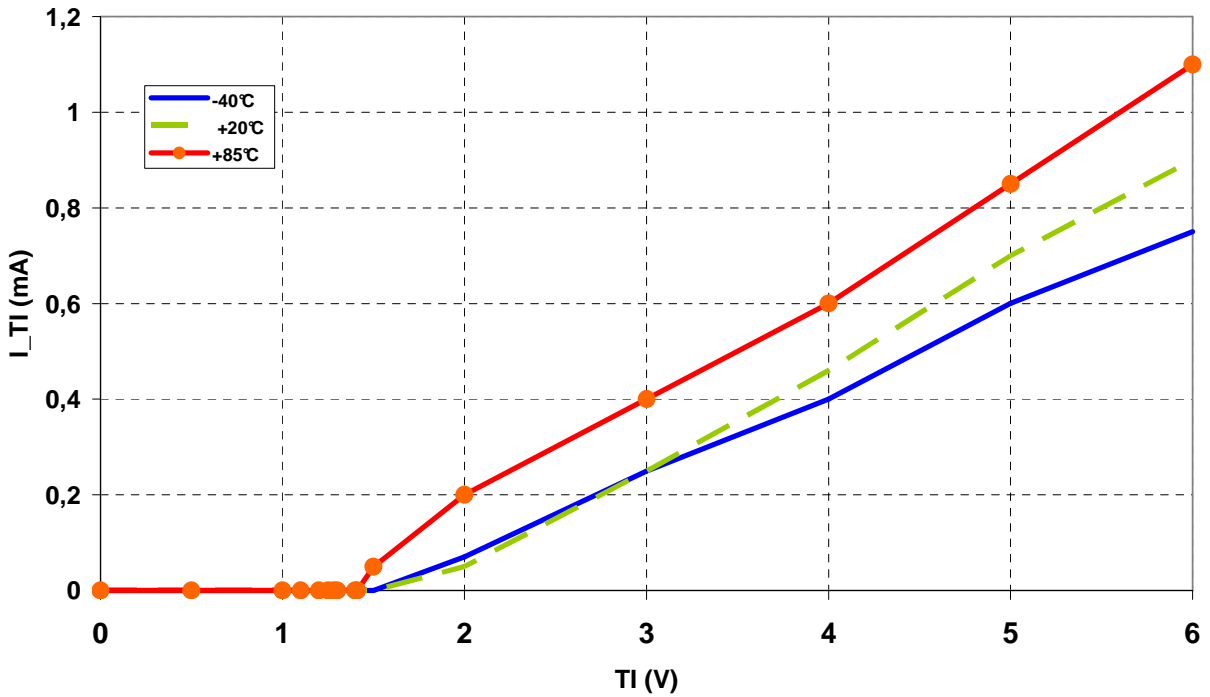


Collector quiescent current versus TI & Vctrl and temperature



Control current versus control voltage & temperature

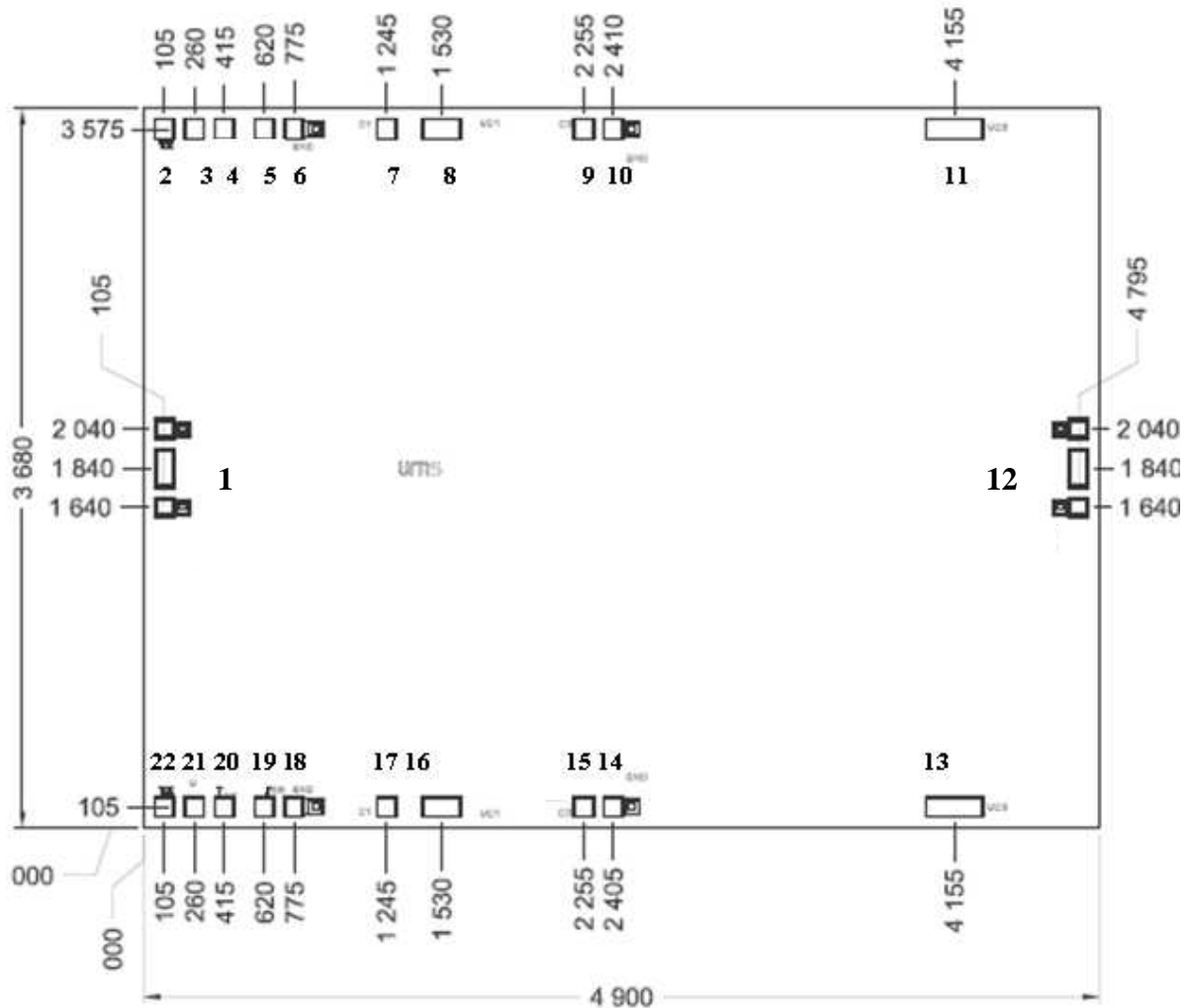
I<sub>TI</sub> (TI)



TTL input current versus TTL voltage and temperature



**Chip Mechanical Data and Pin references**



Units:  $\mu\text{m}$

Chip width and length are given with a tolerance of  $\pm 35\mu\text{m}$

Chip thickness =  $100\mu\text{m} \pm 10\mu\text{m}$

RF pads (1, 12) =  $96 \times 196\mu\text{m}^2$

DC pads (2, 3, 4, 5, 6, 7, 9, 10, 14, 15, 17, 18, 19, 20, 21, 22) =  $96 \times 96\mu\text{m}^2$

DC pads (8, 16) =  $192 \times 96\mu\text{m}^2$

DC pads (11, 13) =  $288 \times 96\mu\text{m}^2$

Pin number	Pin name	Description
1	IN	Input RF
7, 9, 15, 17	C1, C2	Collector current control voltage
2, 22	TI	TTL input
4, 20	TO9	TTL output when $V_{cx}=9V$
5, 19	TO8	TTL output $V_{cx}=8V$
6, 10, 14, 18	GND	Ground (NC)
3, 8, 11, 13, 16, 21	V, Vc1, Vc2	Power supply voltage
12	OUT	Output RF

Ref. : DSCHA81000069 - 10 Mar 10

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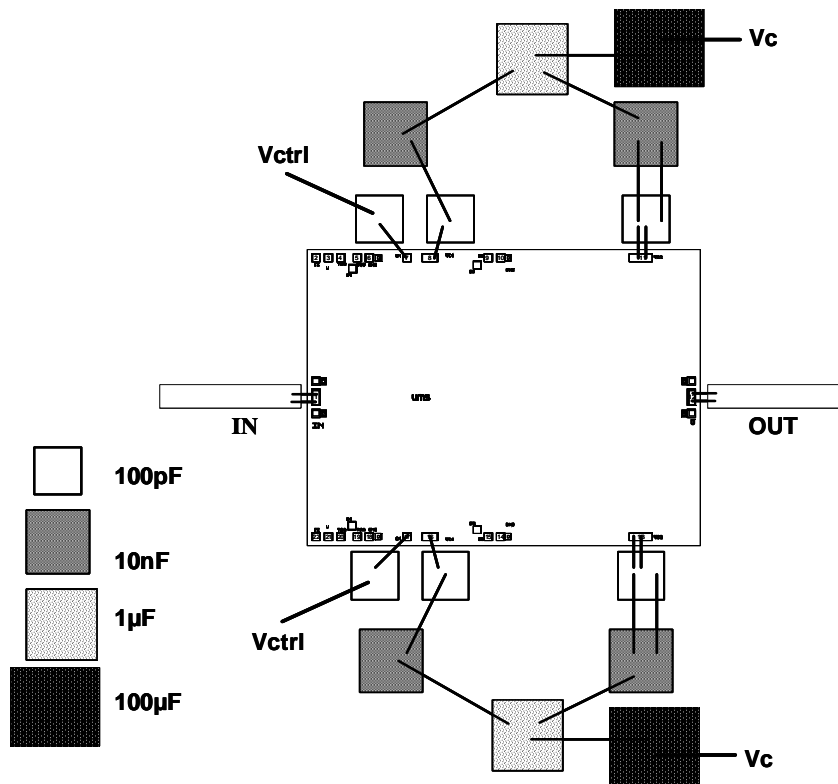
Specifications subject to change without notice

## Bonding recommendations

For thermal and electrical considerations, the chip should be brazed on a metal base plate. The RF, DC and modulation port inter-connections should be done according to the following table:

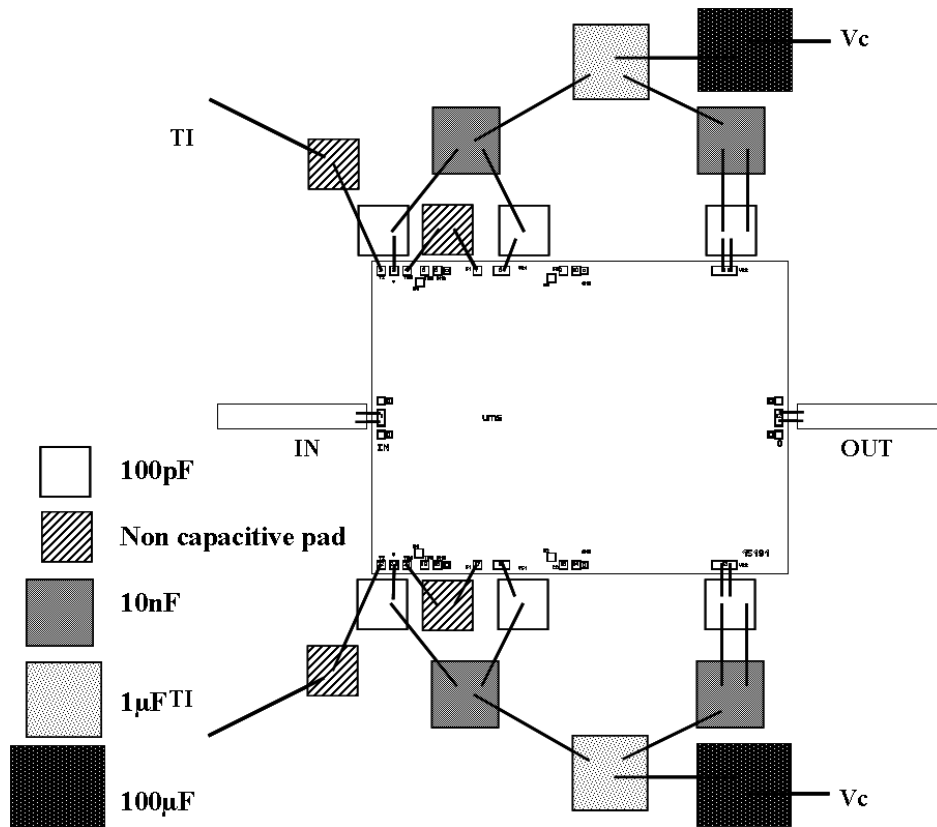
Port	Connection
IN (1)	Inductance ( $L_{\text{bonding}}$ ) = 0.3nH 400 $\mu\text{m}$ length with wire diameter of 25 $\mu\text{m}$ x2
OUT (12)	Inductance ( $L_{\text{bonding}}$ ) = 0.3nH 400 $\mu\text{m}$ length with wire diameter of 25 $\mu\text{m}$ x2
DC pads to 1 <sup>st</sup> decoupling level for double bonding	Inductance ( $L_{\text{bonding}}$ ) = 0.7nH Two 1.2mm length wires with a diameter of 25 $\mu\text{m}$
DC pads to 1 <sup>st</sup> decoupling level for single bonding	Inductance ( $L_{\text{bonding}}$ ) = 1nH One 1.2mm length wires with a diameter of 25 $\mu\text{m}$
1 <sup>st</sup> decoupling level to 2 <sup>nd</sup> decoupling level for double bonding	Inductance ( $L_{\text{bonding}}$ ) = 0.7nH Two 1.2mm length wires with a diameter of 25 $\mu\text{m}$
1 <sup>st</sup> decoupling level to 2 <sup>nd</sup> decoupling level for single bonding	Inductance ( $L_{\text{bonding}}$ ) = 1nH One 1.2mm length wires with a diameter of 25 $\mu\text{m}$

## Assembly recommendations in test fixture (using analogue biasing circuits)



Note: Supply feed should be capacitively by-passed. 25 $\mu\text{m}$  diameter gold wire is to be preferred.

**Assembly recommendations in test fixture  
(using TTL circuits)**



\* Performances obtained with the same accesses connected to the same supply  
Note: Supply feed should be capacitively by-passed. 25µm diameter gold wire is to be preferred.

**Biasing possibilities**

TTL / Vcontrol	V <sub>C1</sub> , V <sub>C2</sub> , V	Connections
Biasing via TTL interface	9V	TO9 connected to C1 and C2 C2 & T08 not connected
Biasing via TTL interface	8V	TO8 connected to C1 and C2 C2 & T09 not connected
Biasing via analogue control device	9V or 8V	C2, V, Ti, TO8, TO9 not connected

## Recommended ESD management

Refer to the application note AN0020 available at <http://www.ums-gaas.com> for ESD sensitivity and handling recommendations for the UMS products.

## Ordering Information

Chip form : CHA8100-99F/00

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